



# BUK9K12-60E

Dual N-channel 60 V, 11.5 mΩ logic level MOSFET

8 May 2014

Product data sheet

## 1. General description

Dual logic level N-channel MOSFET in an LFAK56D (Dual Power-SO8) package using TrenchMOS technology. This product has been designed and qualified to AEC Q101 standard for use in high performance automotive applications.

## 2. Features and benefits

- Dual MOSFET
- Q101 compliant
- Repetitive avalanche rated
- Suitable for thermally demanding environments due to 175 °C rating
- True logic level gate with  $V_{GS(th)}$  rating of greater than 0.5 V at 175 °C

## 3. Applications

- 12 V Automotive systems
- Motors, lamps and solenoid control
- Transmission control
- Ultra high performance power switching

## 4. Quick reference data

Table 1. Quick reference data

| Symbol                                       | Parameter                        | Conditions   |     | Min | Typ  | Max  | Unit |
|--|----------------------------------|--|-----|-----|------|------|------|
| $V_{DS}$                                     | drain-source voltage             | $T_j \geq 25\text{ °C}; T_j \leq 175\text{ °C}$  |     | -   | -    | 60   | V    |
| $I_D$  | drain current                    | $V_{GS} = 5\text{ V}; T_{mb} = 25\text{ °C}; \text{Fig. 2}$  | [1] | -   | -    | 35   | A    |
| $P_{tot}$                                    | total power dissipation          | $T_{mb} = 25\text{ °C}; \text{Fig. 1}$   |     | -   | -    | 68   | W    |
| <b>Static characteristics FET1 and FET2</b>  |                                  |  |     |     |      |      |      |
| $R_{DS(on)}$                                 | drain-source on-state resistance | $V_{GS} = 5\text{ V}; I_D = 15\text{ A}; T_j = 25\text{ °C}; \text{Fig. 11}$                                       |     | -   | 9.5  | 11.5 | mΩ   |
| <b>Dynamic characteristics FET1 and FET2</b> |                                  |  |     |     |      |      |      |
| $Q_{GD}$                                     | gate-drain charge                | $I_D = 15\text{ A}; V_{DS} = 48\text{ V}; V_{GS} = 5\text{ V}; T_j = 25\text{ °C}; \text{Fig. 13}; \text{Fig. 14}$ |     | -   | 8.27 | -    | nC   |

[1] Continuous current is limited by package.



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## 5. Pinning information

Table 2. Pinning information

| Pin | Symbol | Description | Simplified outline   | Graphic symbol   |
|-----|--------|-------------|--|--|
| 1   | S1     | source1     |  <p><b>LFPAK56D (SOT1205)</b></p> |  <p><i>mbk725</i></p> |
| 2   | G1     | gate1       |  |  |
| 3   | S2     | source2     |  |  |
| 4   | G2     | gate2       |  |  |
| 5   | D2     | drain2      |  |  |
| 6   | D2     | drain2      |  |  |
| 7   | D1     | drain1      |  |  |
| 8   | D1     | drain1      |  |  |

## 6. Ordering information

Table 3. Ordering information

| Type number | Package  |  | Version |
|-------------|----------|--|---------|
|             | Name     | Description  |         |
| BUK9K12-60E | LFPAK56D | Plastic single ended surface mounted package (LFPAK56D); 8 leads | SOT1205 |

## 7. Marking

Table 4. Marking codes

| Type number | Marking code |
|-------------|--------------|
| BUK9K12-60E | 91260E       |

## 8. Limiting values

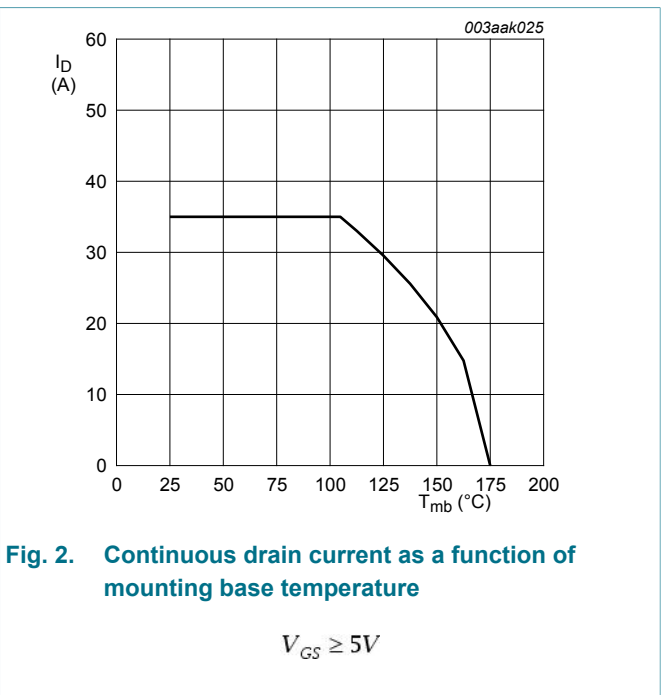
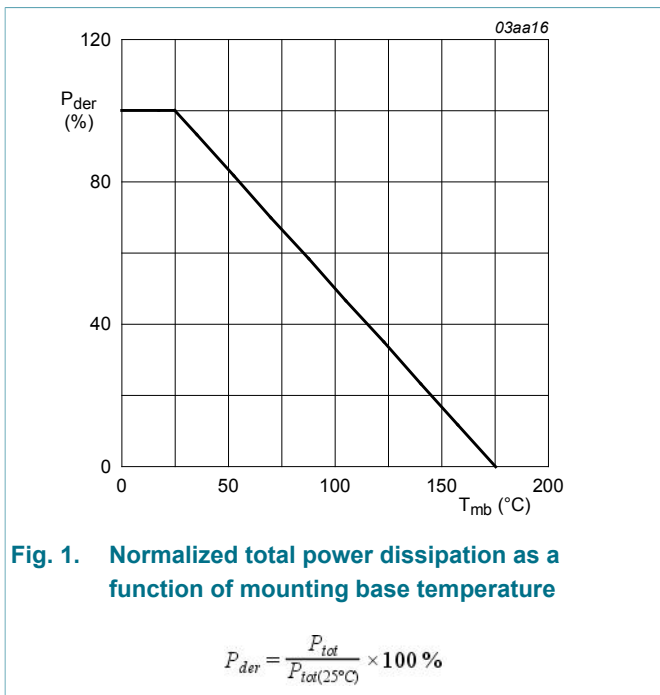
Table 5. Limiting values

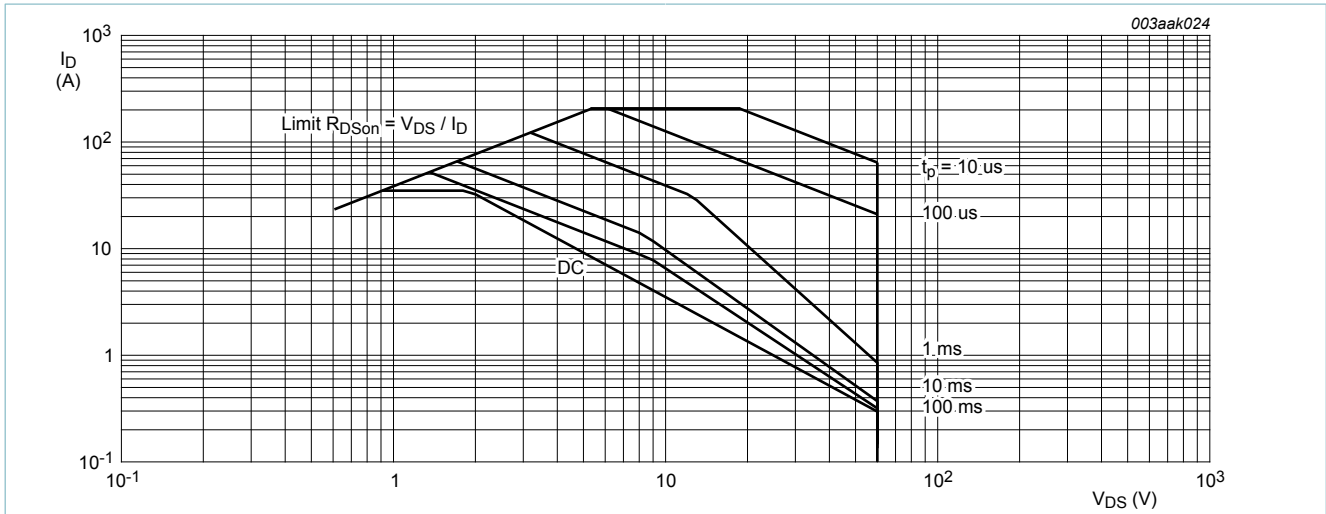
In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol    | Parameter               | Conditions  | Min    | Max | Unit |
|-----------|-------------------------|---|--------|-----|------|
| $V_{DS}$  | drain-source voltage    | $T_j \geq 25\text{ °C}$ ; $T_j \leq 175\text{ °C}$        | -      | 60  | V    |
| $V_{DGR}$ | drain-gate voltage      | $R_{GS} = 20\text{ k}\Omega$                              | -      | 60  | V    |
| $V_{GS}$  | gate-source voltage     | $T_j \leq 175\text{ °C}$ ; DC                             | -10    | 10  | V    |
|           |                         | $T_j \leq 175\text{ °C}$ ; Pulsed                         | [1][2] | 15  | V    |
| $P_{tot}$ | total power dissipation | $T_{mb} = 25\text{ °C}$ ; Fig. 1                          | -      | 68  | W    |
| $I_D$     | drain current           | $T_{mb} = 25\text{ °C}$ ; $V_{GS} = 5\text{ V}$ ; Fig. 2  | [3]    | 35  | A    |
|           |                         | $T_{mb} = 100\text{ °C}$ ; $V_{GS} = 5\text{ V}$ ; Fig. 2 | [3]    | 35  | A    |

| Symbol                                    | Parameter                                    | Conditions  |                        | Min | Max | Unit |
|---|--|---|------------------------|-----|-----|------|
| I <sub>DM</sub>                           | peak drain current                           | T <sub>mb</sub> = 25 °C; pulsed; t <sub>p</sub> ≤ 10 μs; <a href="#">Fig. 3</a>   |                        | -   | 204 | A    |
| T <sub>stg</sub>                          | storage temperature                          |   |                        | -55 | 175 | °C   |
| T <sub>j</sub>                            | junction temperature                         |   |                        | -55 | 175 | °C   |
| <b>Source-drain diode FET1 and FET2</b>   |  |   |                        |     |     |      |
| I <sub>S</sub>                            | source current                               | T <sub>mb</sub> = 25 °C   | <a href="#">[3]</a>    | -   | 35  | A    |
| I <sub>SM</sub>                           | peak source current                          | pulsed; t <sub>p</sub> ≤ 10 μs; T <sub>mb</sub> = 25 °C   |                        | -   | 204 | A    |
| <b>Avalanche Ruggedness FET1 and FET2</b> |  |   |                        |     |     |      |
| E <sub>DS(AL)S</sub>                      | non-repetitive drain-source avalanche energy | I <sub>D</sub> = 35 A; V <sub>sup</sub> ≤ 60 V; V <sub>GS</sub> = 5 V; T <sub>j(init)</sub> = 25 °C; <a href="#">Fig. 4</a> | <a href="#">[4][5]</a> | -   | 118 | mJ   |

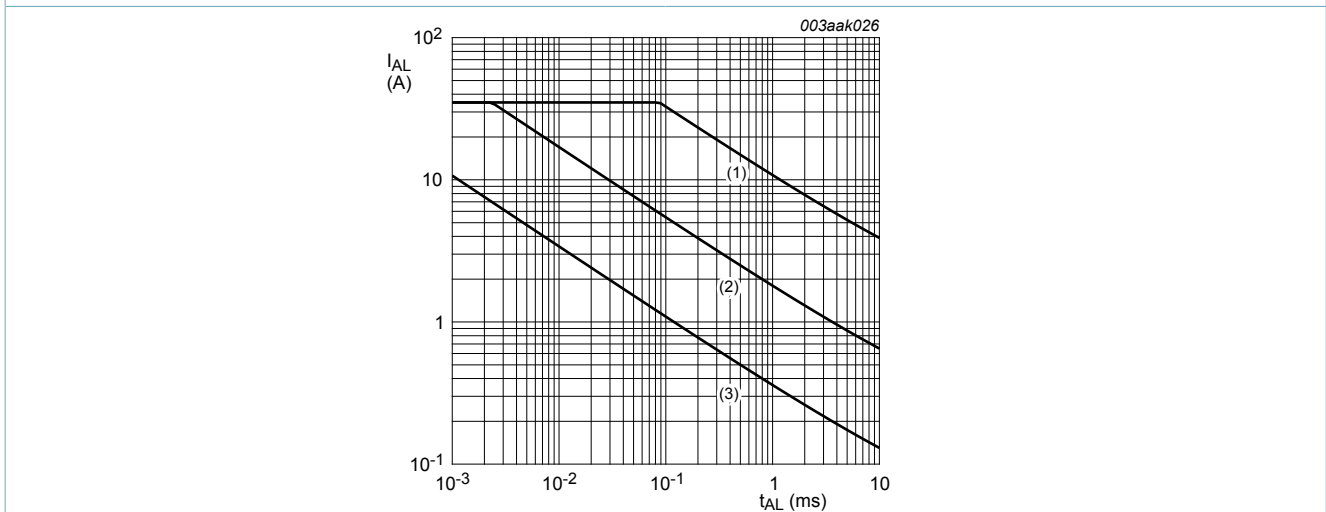
- [1] Accumulated Pulse duration up to 50 hours delivers zero defect ppm
- [2] Significantly longer life times are achieved by lowering T<sub>j</sub> and or V<sub>GS</sub>
- [3] Continuous current is limited by package.
- [4] Refer to application note AN10273 for further information
- [5] Single-pulse avalanche rating limited by maximum junction temperature of 175 °C





**Fig. 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage**

$T_{mb} = 25^{\circ}C$ ;  $I_{DM}$  is a single pulse



**Fig. 4. Avalanche rating; avalanche current as a function of avalanche time**

(1)  $T_{j (int)} = 25^{\circ}C$ ; (2)  $T_{j (int)} = 150^{\circ}C$ ; (3) Repetitive Avalanche

## 9. Thermal characteristics

**Table 6. Thermal characteristics**

| Symbol         | Parameter   | Conditions  | Min | Typ | Max  | Unit |
|----------------|---|---|-----|-----|------|------|
| $R_{th(j-mb)}$ | thermal resistance from junction to mounting base | <a href="#">Fig. 5</a>                                | -   | -   | 2.21 | K/W  |
| $R_{th(j-a)}$  | thermal resistance from junction to ambient       | Minimum footprint; mounted on a printed circuit board | -   | 95  | -    | K/W  |

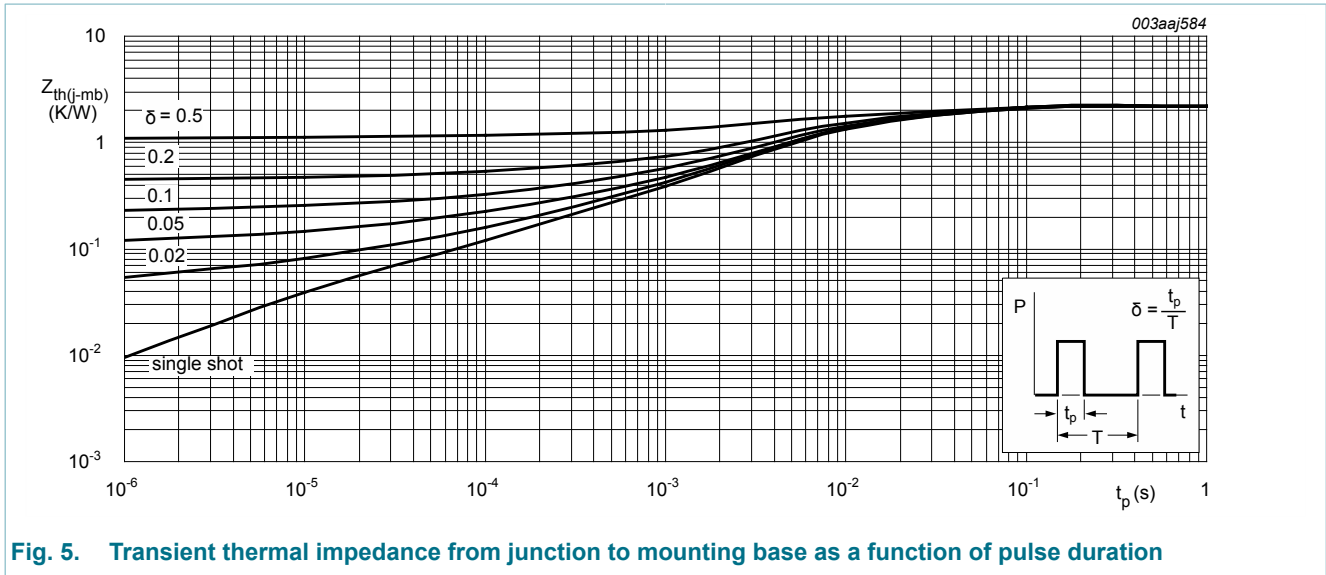


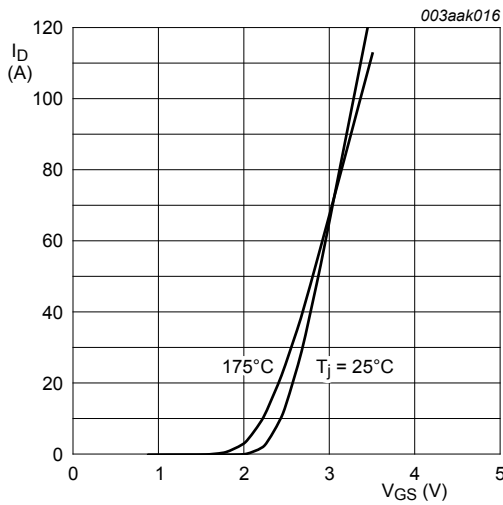
Fig. 5. Transient thermal impedance from junction to mounting base as a function of pulse duration

## 10. Characteristics

Table 7. Characteristics

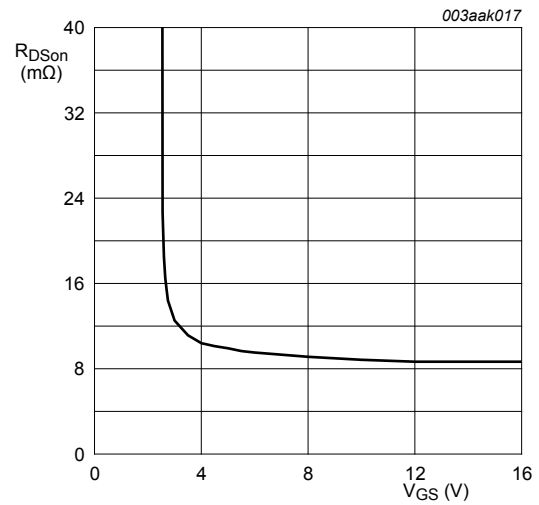
| Symbol                                       | Parameter                        | Conditions  | Min | Typ  | Max  | Unit    |
|--|----------------------------------|---|-----|------|------|---------|
| <b>Static characteristics FET1 and FET2</b>  |                                  |   |     |      |      |         |
| $V_{(BR)DSS}$                                | drain-source breakdown voltage   | $I_D = 250 \mu A; V_{GS} = 0 V; T_j = -55 \text{ }^\circ C$   | 54  | -    | -    | V       |
|  |                                  | $I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 \text{ }^\circ C$  | 60  | -    | -    | V       |
| $V_{GS(th)}$                                 | gate-source threshold voltage    | $I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ }^\circ C;$<br><a href="#">Fig. 9; Fig. 10</a>        | 1.4 | 1.7  | 2.1  | V       |
|  |                                  | $I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 175 \text{ }^\circ C;$<br><a href="#">Fig. 9; Fig. 10</a>       | 0.5 | -    | -    | V       |
|  |                                  | $I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = -55 \text{ }^\circ C;$<br><a href="#">Fig. 9; Fig. 10</a>       | -   | -    | 2.45 | V       |
| $I_{DSS}$                                    | drain leakage current            | $V_{DS} = 60 V; V_{GS} = 0 V; T_j = 25 \text{ }^\circ C$  | -   | 0.02 | 1    | $\mu A$ |
|  |                                  | $V_{DS} = 60 V; V_{GS} = 0 V; T_j = 175 \text{ }^\circ C$   | -   | -    | 500  | $\mu A$ |
| $I_{GSS}$                                    | gate leakage current             | $V_{GS} = -10 V; V_{DS} = 0 V; T_j = 25 \text{ }^\circ C$   | -   | 2    | 100  | nA      |
|  |                                  | $V_{GS} = 10 V; V_{DS} = 0 V; T_j = 25 \text{ }^\circ C$  | -   | 2    | 100  | nA      |
| $R_{DSon}$                                   | drain-source on-state resistance | $V_{GS} = 5 V; I_D = 15 A; T_j = 25 \text{ }^\circ C;$ <a href="#">Fig. 11</a>                              | -   | 9.5  | 11.5 | mΩ      |
|  |                                  | $V_{GS} = 5 V; I_D = 15 A; T_j = 175 \text{ }^\circ C;$<br><a href="#">Fig. 11; Fig. 12</a>                 | -   | 21.5 | 26   | mΩ      |
|  |                                  | $V_{GS} = 10 V; I_D = 15 A; T_j = 25 \text{ }^\circ C;$<br><a href="#">Fig. 11</a>                          | -   | 8.5  | 10.7 | mΩ      |
| <b>Dynamic characteristics FET1 and FET2</b> |                                  |   |     |      |      |         |
| $Q_{G(tot)}$                                 | total gate charge                | $I_D = 15 A; V_{DS} = 48 V; V_{GS} = 5 V;$<br>$T_j = 25 \text{ }^\circ C;$ <a href="#">Fig. 13; Fig. 14</a> | -   | 24.5 | -    | nC      |
| $Q_{GS}$                                     | gate-source charge               |   | -   | 5.4  | -    | nC      |

| Symbol                                  | Parameter                    | Conditions  | Min | Typ  | Max  | Unit |
|---|------------------------------|---|-----|------|------|------|
| $Q_{GD}$                                | gate-drain charge            |   | -   | 8.27 | -    | nC   |
| $C_{iss}$                               | input capacitance            | $V_{GS} = 0\text{ V}; V_{DS} = 25\text{ V}; f = 1\text{ MHz}; T_j = 25\text{ }^\circ\text{C}; \text{Fig. 15}$   | -   | 2602 | 3470 | pF   |
| $C_{oss}$                               | output capacitance           |   | -   | 237  | 284  | pF   |
| $C_{rss}$                               | reverse transfer capacitance |   | -   | 126  | 173  | pF   |
| $t_{d(on)}$                             | turn-on delay time           | $V_{DS} = 48\text{ V}; R_L = 3.2\text{ }\Omega; V_{GS} = 5\text{ V}; R_{G(ext)} = 5\text{ }\Omega; T_j = 25\text{ }^\circ\text{C}; I_D = 15\text{ A}$ | -   | 15.1 | -    | ns   |
| $t_r$                                   | rise time                    |   | -   | 28   | -    | ns   |
| $t_{d(off)}$                            | turn-off delay time          |   | -   | 31.5 | -    | ns   |
| $t_f$                                   | fall time                    |   | -   | 25.3 | -    | ns   |
| <b>Source-drain diode FET1 and FET2</b> |                              |   |     |      |      |      |
| $V_{SD}$                                | source-drain voltage         | $I_S = 10\text{ A}; V_{GS} = 0\text{ V}; T_j = 25\text{ }^\circ\text{C}; \text{Fig. 16}$  | -   | 0.78 | 1.2  | V    |
| $t_{rr}$                                | reverse recovery time        | $I_S = 15\text{ A}; di_S/dt = -100\text{ A}/\mu\text{s}; V_{GS} = 0\text{ V}; V_{DS} = 30\text{ V}; T_j = 25\text{ }^\circ\text{C}$                   | -   | 22.6 | -    | ns   |
| $Q_r$                                   | recovered charge             |   | -   | 18.1 | -    | nC   |



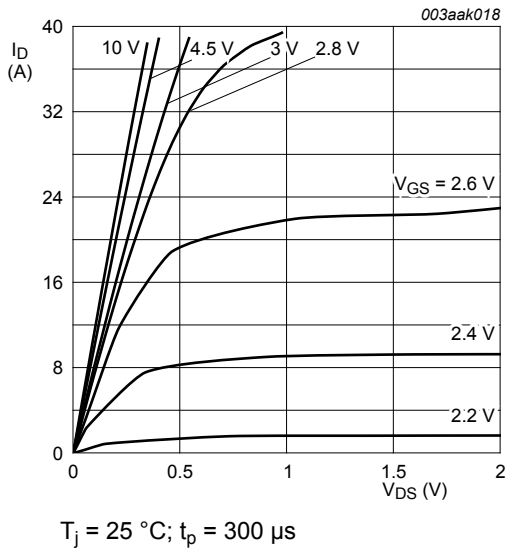
**Fig. 6. Transfer characteristics; drain current as a function of gate-source voltage; typical values**

$V_{DS} = 10\text{ V}$



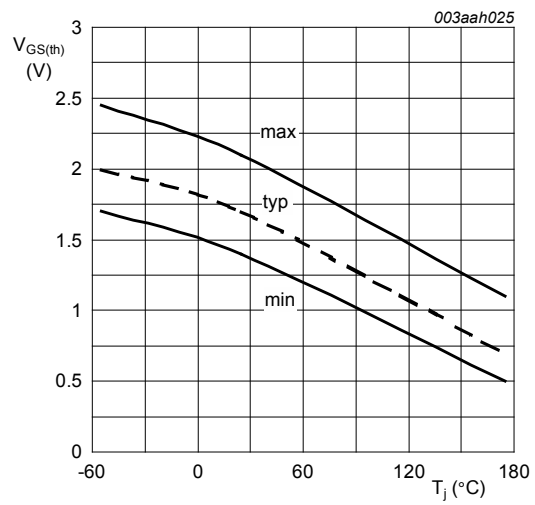
**Fig. 7. Drain-source on-state resistance as a function of gate-source voltage; typical values**

$T_j = 25\text{ }^\circ\text{C}; I_D = 15\text{ A}$



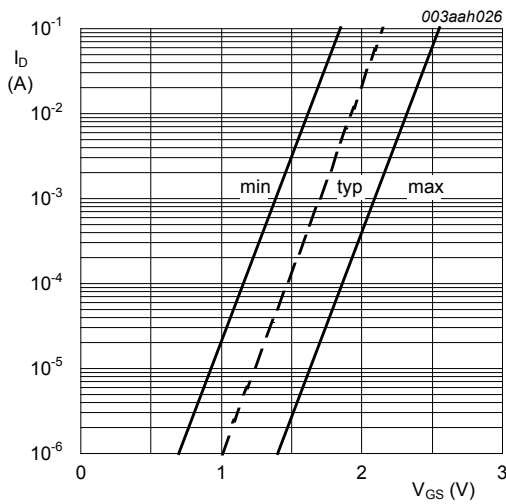
$T_j = 25\text{ }^\circ\text{C}; t_p = 300\text{ }\mu\text{s}$

**Fig. 8. Output characteristics; drain current as a function of drain-source voltage; typical values**



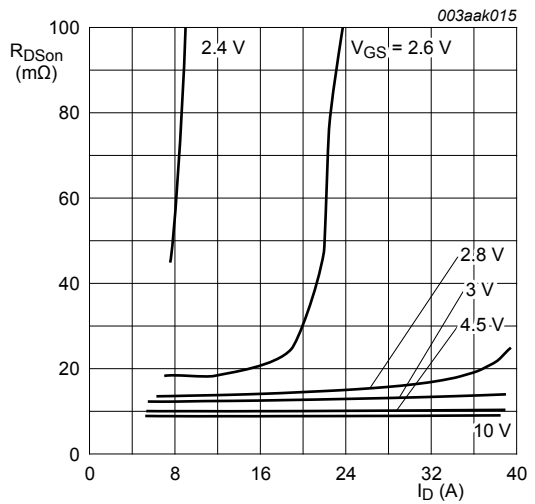
**Fig. 9. Gate-source threshold voltage as a function of junction temperature**

$I_D = 1\text{ mA}; V_{DS} = V_{GS}$



**Fig. 10. Sub-threshold drain current as a function of gate-source voltage**

$T_j = 25\text{ }^\circ\text{C}; V_{DS} = 5\text{ V}$



$T_j = 25\text{ }^\circ\text{C}; t_p = 300\text{ }\mu\text{s}$

**Fig. 11. Drain-source on-state resistance as a function of drain current; typical values**

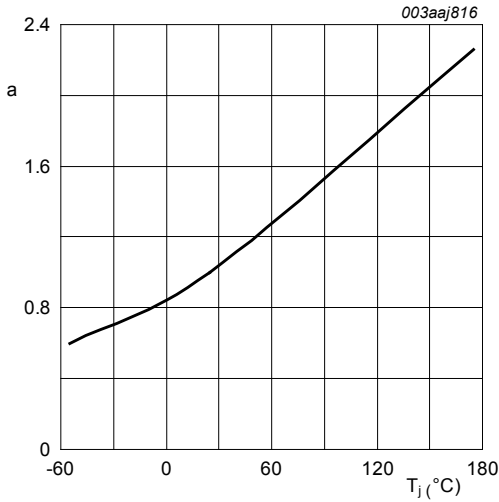


Fig. 12. Normalized drain-source on-state resistance factor as a function of junction temperature

$$a = \frac{R_{DS(on)}}{R_{DS(on)}(25^\circ\text{C})}$$



Fig. 13. Gate charge waveform definitions

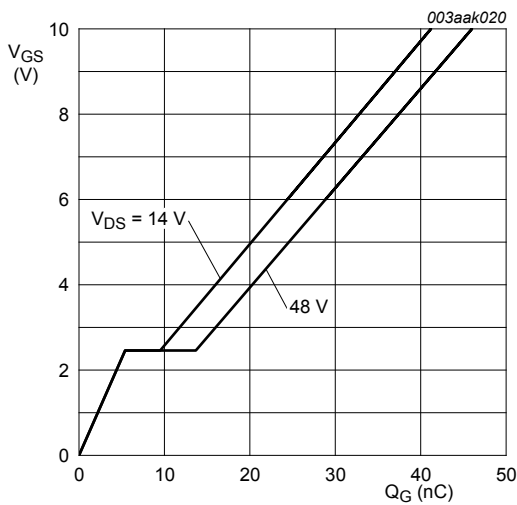


Fig. 14. Gate-source voltage as a function of gate charge; typical values

$$T_j = 25^\circ\text{C}; I_D = 15\text{A}$$

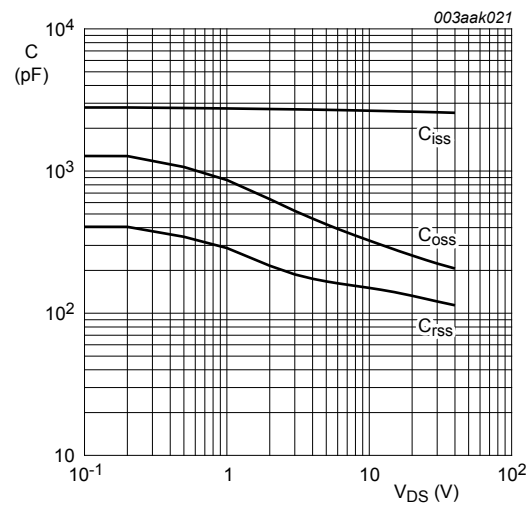


Fig. 15. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

$$V_{GS} = 0\text{V}; f = 1\text{MHz}$$



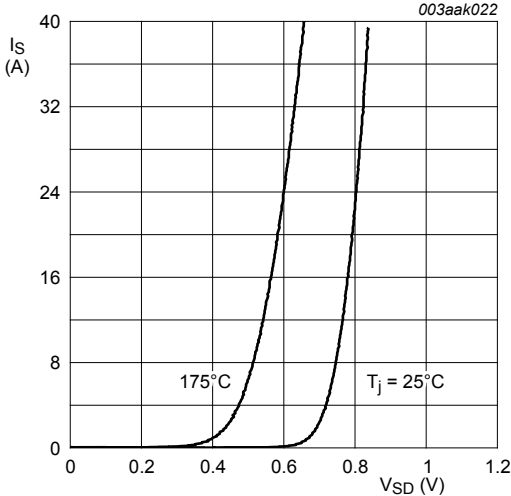
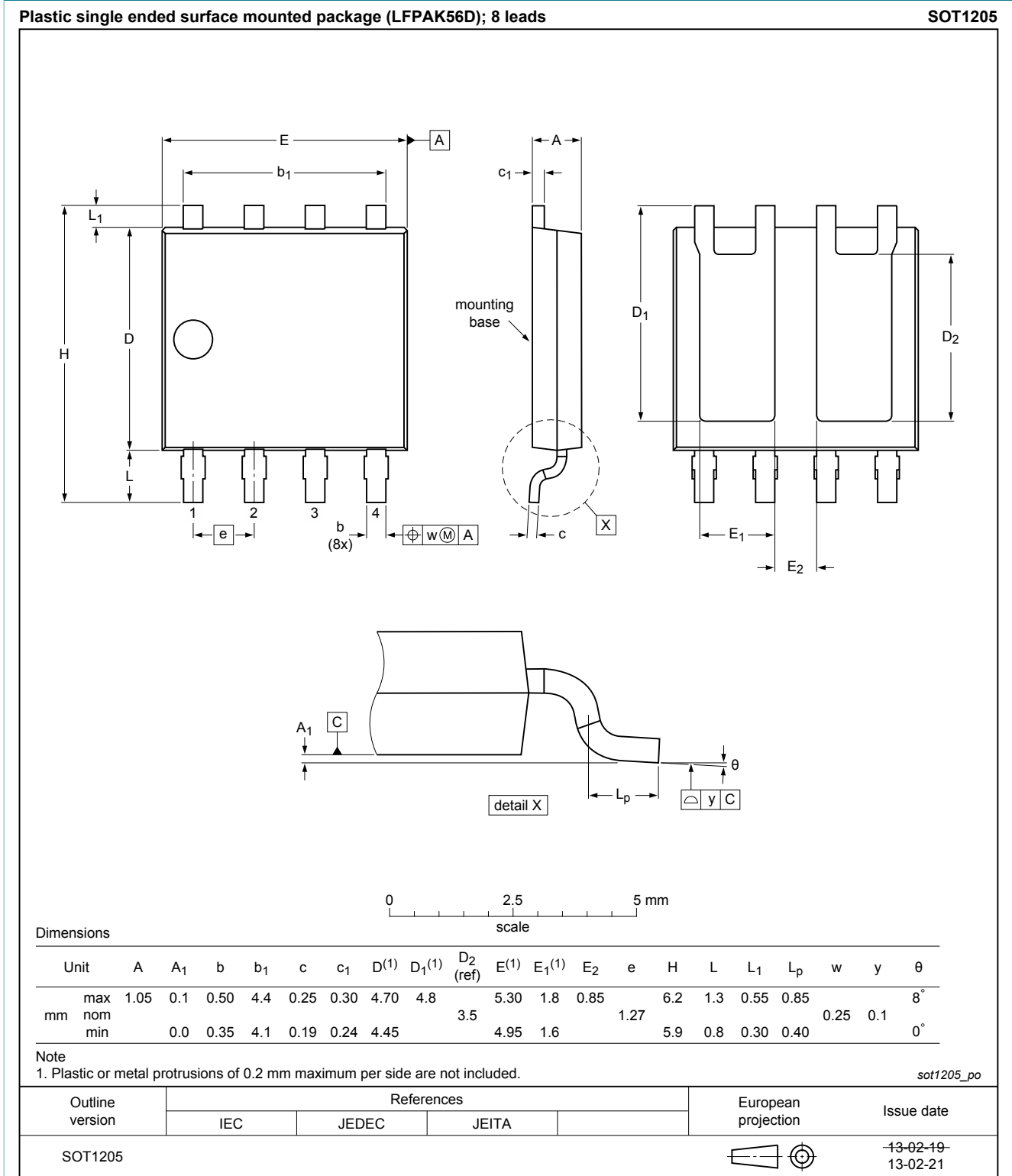


Fig. 16. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values

$$V_{GS} = 0V$$

**11. Package outline**



**Fig. 17. Package outline LPAK56D (SOT1205)**

## 12. Legal information

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| Document status [1][2]         | Product status [3] | Definition  |
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- [2] The term 'short data sheet' is explained in section "Definitions".
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